

EAST Search History

Ref #	Hits	Search Query	DBs	Default Operator	Plurals	Time Stamp
S4	993	Byoung-\$.in.	US-PGPUB; USPAT	ADJ	ON	2007/10/12 12:00
S6	9353	(substrate or wafer) same defect\$3 same detect\$3	US-PGPUB; USPAT	ADJ	ON	2007/05/23 13:51
S7	5841	S6 and (difference or differential)	US-PGPUB; USPAT	ADJ	ON	2007/05/23 13:51
S8	601	S7 and "382".clas.	US-PGPUB; USPAT	ADJ	ON	2007/05/23 13:52
S9	411	S8 and reflect\$3	US-PGPUB; USPAT	ADJ	ON	2007/05/23 16:02
S10	12	("4702606" "4742376" "4805123" "5659172" "5792580" "5793887" "5808735" "5923403" "6097473" "6333992" "6614923" "6700667").PN.	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/05/23 14:06
S11	1	"7020350".pn.	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/05/23 14:06
S12	106	S9 and (defect near2 (reference or template))	US-PGPUB; USPAT	ADJ	ON	2007/05/23 16:59
S13	2	("4736437" "6292582").PN.	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/05/23 16:08
S14	1	S9 and (defect near2 (reference or template) near10 similar\$3)	US-PGPUB; USPAT	ADJ	ON	2007/05/23 17:00
S15	13	S9 and (defect near2 (reference or template) same similar\$3)	US-PGPUB; USPAT	ADJ	ON	2007/05/23 17:01
S16	6	("5475766" "5619429" "5965306" "6016357" "6171731" "6223139").PN.	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/05/23 17:19

S17	1	"5737072".pn.	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/05/23 17:19
S18	1	"10/754013".app.	US-PGPUB; USPAT	ADJ	ON	2007/05/23 18:42
S19	98	S9 and (UV or U\$V or (ultra\$ violet))	US-PGPUB; USPAT	ADJ	ON	2007/05/23 18:43
S20	5	(10/442955 10/749670 10/754013 11/198314). app.	US-PGPUB; USPAT	ADJ	ON	2007/05/24 17:09
S21	14	(09/265840 09/384885 09/940943 10/309166 10/393015 10/442955 10/749670 10/754013 10/801525 10/822055). app.	US-PGPUB; USPAT	ADJ	ON	2007/05/24 17:10
S22	497	382/144.ccls.	US-PGPUB; USPAT	ADJ	ON	2007/05/24 17:14
S23	132	S22 and (substrate or wafer) same defect\$3 same detect\$3	US-PGPUB; USPAT	ADJ	ON	2007/05/24 17:14
S24	783	382/145.ccls.	US-PGPUB; USPAT	ADJ	ON	2007/05/24 17:15
S25	930	382/147-150.ccls.	US-PGPUB; USPAT	ADJ	ON	2007/05/24 17:15
S26	419	S24 and reflect\$3	US-PGPUB; USPAT	ADJ	ON	2007/05/24 17:16
S27	9371	(substrate or wafer) same defect\$3 same detect\$3	US-PGPUB; USPAT	ADJ	ON	2007/05/24 17:16
S28	5852	S27 and (difference or differential)	US-PGPUB; USPAT	ADJ	ON	2007/05/24 17:16
S29	601	S28 and "382".clas.	US-PGPUB; USPAT	ADJ	ON	2007/05/24 17:16
S30	411	S29 and reflect\$3	US-PGPUB; USPAT	ADJ	ON	2007/05/24 17:16
S31	113	S26 and S30	US-PGPUB; USPAT	ADJ	ON	2007/05/24 17:16
S32	1	("5153444").PN.	US-PGPUB; USPAT	ADJ	ON	2007/05/24 17:21
S33	141	(Byoung-\$ near3 Lee). in.	US-PGPUB; USPAT	ADJ	ON	2007/10/12 12:00
S34	15	(Deok-Yong near3 Kim). in.	US-PGPUB; USPAT	ADJ	ON	2007/10/12 12:01

S36	141	(Byoung-\$ near3 Lee). in.	US-PGPUB; USPAT	ADJ	ON	2007/10/12 12:03
S37	2	S36 and "S44"	US-PGPUB; USPAT	ADJ	ON	2007/10/12 12:04
S38	15	(Deok-Yong near3 Kim). in.	US-PGPUB; USPAT	ADJ	ON	2007/10/12 12:04
S39	4	S36 and S38	US-PGPUB; USPAT	ADJ	ON	2007/10/12 12:04
S40	523	382/144.ccls.	US-PGPUB; USPAT	ADJ	ON	2007/10/12 12:06
S41	825	382/145.ccls.	US-PGPUB; USPAT	ADJ	ON	2007/10/12 12:05
S42	668	382/149.ccls.	US-PGPUB; USPAT	ADJ	ON	2007/10/12 12:05
S43	619	382/151.ccls.	US-PGPUB; USPAT	ADJ	ON	2007/10/12 12:05
S44	2234	(S40 OR S41 OR S42 OR S43)	US-PGPUB; USPAT	ADJ	ON	2007/10/12 12:06
S45	16	S44 and ((match\$3 or correspond\$3) same ((reference or specific) near3 defect) same pixel)	US-PGPUB; USPAT	ADJ	ON	2007/10/12 15:07
S46	67	S44 and ((match\$3 or correspond\$3) same ((reference or specific) near3 defect) and pixel)	US-PGPUB; USPAT	ADJ	ON	2007/10/12 12:19
S47	26	S44 and ((match\$3 or correspond\$3) same ((reference or specific) near3 defect) and CCD)	US-PGPUB; USPAT	ADJ	ON	2007/10/12 12:25
S48	2	S44 and ((match\$3 or correspond\$3) same ((specific) near3 defect) same pixel)	US-PGPUB; USPAT	ADJ	ON	2007/10/12 12:26
S49	26	S44 and ((match\$3 or correspond\$3) same ((specific) near3 defect))	US-PGPUB; USPAT	ADJ	ON	2007/10/12 14:45
S50	13	("6483938").URPN.	USPAT	ADJ	ON	2007/10/12 12:31
S51	48	S44 and ((classify\$3 or classification) same ((specific) near3 defect))	US-PGPUB; USPAT	ADJ	ON	2007/10/12 12:40

S52	37	((match\$3 or correspond\$3) same ((reference or specific) near3 defect) same pixel)	US-PGPUB; USPAT	ADJ	ON	2007/10/12 14:44
S53	21	S52 not S45	US-PGPUB; USPAT	ADJ	ON	2007/10/12 14:26
S54	23	("20020130262" "20020153916" "20030028343" "20030102436" "20030205326" "20030236586" "20050033538" "5592099" "5592100" "5640539" "5656811" "5673028" "5757198" "5852793" "6337533" "6466895" "6539106" "6635872" "6670610" "6799130" "6864955" "6867606" "6882745").PN.	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/10/12 14:27
S55	2	((match\$3 or correspond\$3) same (database near3 defect) same pixel)	US-PGPUB; USPAT	ADJ	ON	2007/10/12 14:44
S56	18	S44 and ((match\$3 or correspond\$3) same (database near3 defect))	US-PGPUB; USPAT	ADJ	ON	2007/10/12 14:55
S57	0	S44 and (((pixel near2 based) or (pixel-based)) same (database near3 defect))	US-PGPUB; USPAT	ADJ	ON	2007/10/12 14:55
S58	1	((((pixel near2 based) or (pixel-based)) same (database near3 defect))	US-PGPUB; USPAT	ADJ	ON	2007/10/12 14:56
S59	18	((((pixel near2 based) or (pixel-based)) and (database near3 defect))	US-PGPUB; USPAT	ADJ	ON	2007/10/12 14:59

S60	78	((CCD or CMOS) same (manufactur\$3)) and ((defect\$3 near3 pixel) near6 detect\$3)	US-PGPUB; USPAT	ADJ	ON	2007/10/12 15:06
S61	10	"382".clas. and S60	US-PGPUB; USPAT	ADJ	ON	2007/10/12 15:01
S62	0	((CCD or CMOS) same (manufactur\$3)) and (((defect\$3 near3 pixel) near6 detect\$3) same database)	US-PGPUB; USPAT	ADJ	ON	2007/10/12 16:12
S63	18	S44 and ((match\$3 or correspond\$3) same ((reference or specific) near3 (defect\$3 or anomaly)) same pixel)	US-PGPUB; USPAT	ADJ	ON	2007/10/12 15:07
S64	363	((CCD or CMOS) same inspect\$3) and (defect \$3 near3 pixel)	US-PGPUB; USPAT	ADJ	ON	2007/10/12 16:13
S65	139	"382".clas. and (((CCD or CMOS) same inspect \$3) and (defect\$3 near3 pixel))	US-PGPUB; USPAT	ADJ	ON	2007/10/12 16:39
S66	11	"382".clas. and (((CCD or CMOS) same inspect \$3) same (defect\$3 near3 pixel))	US-PGPUB; USPAT	ADJ	ON	2007/10/12 16:33
S67	2	((((CCD or CMOS) near3 sensor) same inspect \$3) same (defect\$3 near3 pixel)	US-PGPUB; USPAT	ADJ	ON	2007/10/12 16:38
S68	0	((((CCD or CMOS) near3 chip) same inspect\$3) same (defect\$3 near3 pixel)	US-PGPUB; USPAT	ADJ	ON	2007/10/15 10:20
S69	6	"382".clas. and (((((CCD or CMOS) near3 substrate) same inspect \$3) and (defect\$3 near3 pixel))	US-PGPUB; USPAT	ADJ	ON	2007/10/12 17:24
S70	11	("4398177" "4870357" "4907282" "5038048" "5058178" "5137362" "5224176" "5608816" "5872870" "6396943" "6408109").PN.	US-PGPUB; USPAT; USOCR	ADJ	ON	2007/10/12 16:42

S71	0	(pixel adj2 by adj2 pixel) and (((CCD or CMOS) near3 substrate) same inspect \$3) and (defect\$3 near3 pixel))	US-PGPUB; USPAT	ADJ	ON	2007/10/12 17:27
S72	0	(pixel adj2 by adj2 pixel) and (((CCD or CMOS) same inspect \$3) and (defect\$3 near3 pixel))	US-PGPUB; USPAT	ADJ	ON	2007/10/12 17:30
S73	0	(pixel adj2 by adj2 pixel) and (((CCD or CMOS) same inspect \$3))	US-PGPUB; USPAT	ADJ	ON	2007/10/12 17:27
S74	0	(pixel adj2 by adj2 pixel)	US-PGPUB; USPAT	ADJ	ON	2007/10/12 17:27
S75	5	(pixel-by-pixel) and (((CCD or CMOS) near3 substrate) same inspect\$3) and (defect \$3 near3 pixel))	US-PGPUB; USPAT	ADJ	ON	2007/10/12 17:27
S76	35	(pixel-by-pixel) and (((CCD or CMOS) same inspect\$3) and (defect \$3 near3 pixel))	US-PGPUB; USPAT	ADJ	ON	2007/10/12 17:30
S78	5	((((CCD or CMOS)) near3 inspect\$3) same (defect\$3 near3 pixel)	US-PGPUB; USPAT	ADJ	ON	2007/10/15 10:28
S79	29	((((CCD or CMOS)) near3 inspect\$3) and (SEM)	US-PGPUB; USPAT	ADJ	ON	2007/10/15 10:50
S80	183	(pixel near3 inspect\$3) and (SEM)	US-PGPUB; USPAT	ADJ	ON	2007/10/15 10:51
S81	1	"5233191".pn.	US-PGPUB; USPAT	ADJ	ON	2007/10/15 17:03
S82	161	(Byoung-\$ near3 Lee). in.	US-PGPUB; USPAT	ADJ	ON	2008/04/19 08:39
S83	15	(Deok-Yong near3 Kim). in.	US-PGPUB; USPAT	ADJ	ON	2008/04/19 08:40
S84	4	S82 and S83	US-PGPUB; USPAT	ADJ	ON	2008/04/19 08:40
S85	573	382/144.ccls.	US-PGPUB; USPAT	ADJ	ON	2008/04/19 08:40
S86	890	382/145.ccls.	US-PGPUB; USPAT	ADJ	ON	2008/04/19 08:40

S87	712	382/149.ccls.	US-PGPUB; USPAT	ADJ	ON	2008/04/19 08:40
S88	647	382/151.ccls.	US-PGPUB; USPAT	ADJ	ON	2008/04/19 08:40
S89	573	382/144.ccls.	US-PGPUB; USPAT	ADJ	ON	2008/04/19 08:40
S90	890	382/145.ccls.	US-PGPUB; USPAT	ADJ	ON	2008/04/19 08:40
S91	2390	(S89 OR S90 OR S87 OR S88)	US-PGPUB; USPAT	ADJ	ON	2008/04/19 08:40
S92	17	S91 and ((match\$3 or correspond\$3) same ((reference or specific) near3 defect) same pixel)	US-PGPUB; USPAT	ADJ	ON	2008/04/19 08:40
S97	1	"7037735".pn. and ((user or operator) near6 threshold\$3)	US-PGPUB; USPAT	ADJ	ON	2008/04/19 08:45
S98	0	"7037735".pn. and ((pre \$set) near6 threshold \$3)	US-PGPUB; USPAT	ADJ	ON	2008/04/19 08:47
S99	1	"7037735".pn. and ((set) near6 threshold \$3)	US-PGPUB; USPAT	ADJ	ON	2008/04/19 08:47
S100	254	((semi\$conductor or mask or wafer) near3 defect) same ((difference or compar \$3) same (adjacent or neighbor\$3))	US-PGPUB; USPAT	ADJ	ON	2008/04/19 15:42
S101	2	S100 and (siz\$3 near3 (threshold\$3))	US-PGPUB; USPAT	ADJ	ON	2008/04/19 15:42
S102	2	S100 and (siz\$3 near3 (threshold\$3 or criteri \$2))	US-PGPUB; USPAT	ADJ	ON	2008/04/19 15:50
S103	20	S100 and (siz\$3 near3 compar\$4)	US-PGPUB; USPAT	ADJ	ON	2008/04/19 15:51
S104	12	"382".clas. and (((CCD or CMOS) same inspect \$3) same (defect\$3 near3 pixel))	US-PGPUB; USPAT	ADJ	ON	2008/04/19 16:11

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